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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination STADLMAYR ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| U.S. PATENT DOCUMENTS | | | | |

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|--|-----------------|---------------------|----------------|
| * | A | US-4,120,425 A | 10-1978 | Bethurum, George M. | 222/146.6 |
| * | B | US-5,131,440 A | 07-1992 | Quinn, Thomas P. | 141/63 |
| * | C | US-5,720,148 A | 02-1998 | Bedin et al. | 53/167 |
| * | D | US-6,308,752 B1 | 10-2001 | Tsukano et al. | 141/290 |
| * | E | US-6,457,495 B1 | 10-2002 | Meheen, Dave | 141/40 |
| * | F | US-6,474,368 B2 | 11-2002 | Clusserath et al. | 141/6 |
| * | G | US-2003/0232114 A1 | 12-2003 | Dekleva, Nikola | 426/312 |
| H | US- | | | | |
| I | US- | | | | |
| J | US- | | | | |
| K | US- | | | | |
| L | US- | | | | |
| M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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